

1st Day

Tuesday, 14 March 2017

Chair: Michael Schulz; Physikalisch-Technische Bundesanstalt; Germany

12:00 Arrival / Registration, Lunch and Table Top Presentations

13:00 Conference Opening, Overview and Outlook
Frank Löffler; CC UPOB e.V.; Germany

Session – Aspherical Surfaces

13:15 Holistic Measurement of Aspheric Lenses by Model-Based Metrology; Rainer Tutsch; Technical University Braunschweig; Germany

13:45 In Measurements we Trust - Decenter and Tilt of Aspheres
Ulrike Fuchs; Asphericon GmbH; Germany

14:15 Non-Contact Measurement of Aspheric Surfaces Based on Point Laser Interferometer; Xiaofei Diao; National Institute of Metrology; China

14:45 Coffee Break and Table Top Presentations

15:15 Frequency Scanning Interferometry for Measurement of Aspherical Surfaces; Pavel Psota; TOPTEC; Czech Republic

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15:45 Standardization in Asphere and Freeform Metrology
Michael Schulz; Physikalisch-Technische Bundesanstalt; Germany

Session – Moulded and Small Precision Optics

16:15 Lessons Learned From the Optical Metrology of Moulded Aspheres for Cell Phone Cameras
Xavier Colonna de Lega; Zygo Corporation / AMETEK Germany GmbH; Germany

16:45 Component-Level Test of Moulded Freeform Optics for LED Beam Shaping Using Experimental Ray Tracing
Tobias Binkele; Hochschule Bremen; Germany

17:20 Closing

19:00 Conference Dinner



8th HLEM 2017 - Asphere Metrology

Detailed Programme

V.6.1

2nd Day Wednesday, 15 March 2017 - **Morning**
Chair: Gunter Schneider; Schneider GmbH & Co. KG; Germany

9:00 Opening

Session – In Situ- Measurements and Manufacturing

9:05 Deflectometric Acquisition of Large Optical Surfaces “DaOS”
Using a New Physical Measurement Principle:
Vignetting Field Stop Procedure
Engelbert Hofbauer Technische Hochschule Deggendorf; Germany

9:35 Challenges in Ultra-Precision High Performance Cutting
Timo Dörgeloh; LFM University of Bremen; Germany

10:05 Manufacturing of Freeform Optics Using Plasma Jet Machining
Thomas Arnold; IOM Leipzig; Germany

10:35 Coffee Break and Table Top Presentations

Session – Freeform and Cylindrical Surfaces

11:05 Optical Measurement of Aspheres and Freeforms –
Current Solutions and Challenges
Stefan Mühlig; Mahr GmbH – Standort Jena; Germany

11:35 Interferometric Testing of Strong Aspheres with Diffractive
Fizeau Null Lenses (DFNL); Frank Weidner; Dioptic GmbH; Germany

12:05 UA3P - Nano Measurement Accuracy on Asphere and Freeform
Surfaces; Tomofumi Morishita; Panasonic Production Engineering Co.,Ltd.; Japan

2nd Day Wednesday, 15 March 2017 - **Afternoon**
Chair: Jean-Michel Asfour; Dioptic GmbH; Germany

12:35 Lunch and Table Top Presentations

13:30 Freeform Metrology Using Subaperture Stitching Interferometry
Jean-Pierre Lormeau; QED Technologies; United States

14:00 Challenges in Metrology of Mirror Segments for X-Ray
Telescopes; Anne-Catherine Probst; Hochschule Aschaffenburg; Germany

14:30 Metrology of Mild Freeform and Cylinder Optics Based on a
Scanning Interferometer
Marc Wendel; Ametek GmbH - Business Division Luphos; Germany

15:00 Characterization of Optical Components by Novel PTB-
Technologies
Bernhard Smandek; Physikalisch-Technische Bundesanstalt; Germany

15:30 Summary and Outlook
Jean-Michel Asfour; Dioptic GmbH; Germany

15:40 **Conference Closing**

Departure

